

Page 1 of 6

Report No.: BTEK240111002AE002

FCC ID: 2AATP-TP350

# **RF Exposure Evaluation Report**

Application No.: BTEK240111002AE

Applicant: SHENZHEN ECARE ELECTRONICS CO., LTD

Address of Applicant: B201/B401/B501/B601, Hua Li Industrial Building, 404 Yu An Road, Bao An,

Shenzhen, Guang Dong, China

Manufacturer: SHENZHEN ECARE ELECTRONICS CO., LTD

Address of Manufacturer: B201/B401/B501/B601, Hua Li Industrial Building, 404 Yu An Road, Bao An,

Shenzhen, Guang Dong, China

Factory: SHENZHEN ECARE ELECTRONICS CO., LTD

Address of Factory: B201/B401/B501/B601, Hua Li Industrial Building, 404 Yu An Road, Bao An,

Shenzhen, Guang Dong, China

**Equipment Under Test (EUT):** 

**EUT Name:** Bluetooth Thermometer/Hygrometer

Model No.: TP350, TP350W, C50

Please refer to section 3 of this report which indicates which model was

actually tested and which were electrically identical.

Trade Mark: N/A

Standard(s): 47 CFR Part 2 Subpart J Section 2.1093

**Date of Receipt:** 2024-01-11

**Date of Test:** 2024-01-11 to 2024-01-27

**Date of Issue:** 2024-01-31

Test Result: Pass\*

\* In the configuration tested, the EUT complied with the standards specified above.

Damon Su EMC Laboratory Manager

ShenZhen BANTEK Testing Co.,Ltd.

Add: A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street

Bao'an District, Shenzhen, Guangdong, China 518104





Page 2 of 6

Report No.: BTEK240111002AE002

Revision Record				
Version	Chapter	Date	Modifier	Remark
01		2024-01-31		Original

Authorized for issue by:	870 )]]	
BLE	Elma. Kang	
0	Elma Yang /Project Engineer	-
	0 0	0 0
	Carl. Yang	
BIEK	Carl Yang /Reviewer	

ShenZhen BANTEK Testing Co.,Ltd.

Add: A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street

Bao'an District, Shenzhen, Guangdong, China 518104





Page 3 of 6

Report No.: BTEK240111002AE002

## 2 Contents

				Page
1	COV	/ER PAGE		1
2	CON	NTENTS	0 0	3
3	GEN	IERAL INFORMATION		4
	3.1 3.2 3.3 3.4 3.5	DETAILS OF E.U.T  DESCRIPTION OF SUPPORT UNITS  TEST LOCATION  DEVIATION FROM STANDARDS  ABNORMALITIES FROM STANDARD CONDITIONS		
4	TES	T REQUIREMENT  Test Data and Test Result		6
5		CONSTRUCTIONAL DETAILS		



Add: A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street

Bao'an District, Shenzhen, Guangdong, China 518104





Page 4 of 6

Report No.: BTEK240111002AE002

#### 3 General Information

#### 3.1 Details of E.U.T.

Power supply:	DC 3V from 2 AAA Batteries	
For BLE		
Operation Frequency:	2402MHz to 2480MHz	
Modulation Type:	GFSK	
Channel Spacing:	2MHz	
Date Rate:	1Mbps, 2Mbps	
Number of Channels:	40	
Antenna Type:	PCB Antenna	
Antenna Gain:	5 dBi	
Sample No.:	BTEK240111002AE-01	

Remark: The information in this section is provided by the applicant or manufacturer, BANTEK is not liable to the accuracy, suitability, reliability or/and integrity of the information.

Model No.: TP350, TP350W, C50

Only the model TP350 was tested. According to the declaration from the applicant, the electrical circuit design, layout, components used, internal wiring and functions of other models are identical for the above models, with only difference on model No.

#### 3.2 Description of Support Units

The EUT has been tested as an independent unit.

ShenZhen BANTEK Testing Co.,Ltd.

Add: A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street

Bao'an District, Shenzhen, Guangdong, China 518104





Page 5 of 6 Report No.: BTEK240111002AE002

#### 3.3 Test Location

All tests were performed at:

Shenzhen BANTEK Testing Co., Ltd.

A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street, Bao'an District,

Shenzhen, Guangdong, China 518104

Tel:0755-2334 4200 Fax: 0755-2334 4200

FCC Registration Number: 264293 Designation Number: CN1356 No tests were sub-contracted.

#### 3.4 Deviation from Standards

None

#### 3.5 Abnormalities from Standard Conditions

None

ShenZhen BANTEK Testing Co.,Ltd.

Add: A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street

Bao'an District, Shenzhen, Guangdong, China 518104





Page 6 of 6

Report No.: BTEK240111002AE002

## 4 Test Requirement

KDB447498 D01 General RF Exposure Guidance v06, Clause 4.3.1(a)

[(max. power of channel, including tune-up tolerance, mW) / (min. test separation distance, mm)] •  $[\sqrt{f(GHz)}] \le 3.0$ 

Where

- -f(GHz) is the RF channel transmit frequency in GHz
- -Power and distance are rounded to the nearest mW and mm before calculation
- -The test exclusions are applicable only when the minimum test separation distance is  $\leq$  50 mm, and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is  $\leq$  5 mm, a distance of 5 mm according to 4.1 f) is applied to determine SAR test exclusion.

#### 4.1 Test Data and Test Result

Туре	Frequency (MHz)	Conducted Power (dBm)	Maximum Tune-up (dBm)	Calculating data	Limit	Result
BLE	2402	-0.71	0	0.310	3.0	Pass

Note: The exposure evaluation safety distance is 5mm.

### 5 EUT Constructional Details

Refer to Appendix - External and Internal Appendix EUT Photos.

ShenZhen BANTEK Testing Co.,Ltd.

Add: A5&A6, Building B1&B2, No.45 Gangtou Road, Bogang Community, Shajing Street

Bao'an District, Shenzhen, Guangdong, China 518104

Tel: +(86)755-2334 4200 E-mail: Service@btek-lab.com Web

Web: www.btek-lab.com

